 rch Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/945,171	SMITH ET AL.	
Examiner	Art Unit	
Erin M. File	2611	

SEARCHED				
Class	Subclass	Date	Examiner	
375	297	6/25/2006	EMF	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	6/25/2006	EMF		